Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/648,064	CHANG ET AL.
Examiner	Art Unit
Dennis Myint	2162

SEARCHED					
Class	Subclass	Date	Examiner		
364	200	2/8/2006	DM		
360	·72	2/8/2006	DM		
711	114	2/9/2006	DM		
700	159	7/6/2006			
		-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (EPO; JPO; IBM; USPAT)	2/8/2006	DM	
EAST (EPO; JPO; IBM; USPAT)	2/8/2006	DM	
NPL: ACM site	2/8/2006	DM	
EAST (EPO; JPO; IBM; USPAT)	7/6/2006	DM	